 arch Notes

 Application/Control No.	Control No. Applicant(s)/Patent under Reexamination		
10/075,367	KENNETH, O'HAGAN		
Examiner	Art Unit		
Erin M. File	2634		

SEARCHED				
Class	Subclass	Date	Examiner	
375	142	1/10/2006	EMF	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	1/10/2006	EMF